DIAGNOSTIC AND DETECTORS FOR CHARGING AND DAMAGE OF DIELECTRICS IN HIGH-GRADIENT ACCELERATORS

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Research Problem Statement:

• Research is aimed to address issues of *analysis of high repetition rate effects in Dielectric Wakefield Accelerators*,

• Specifically,

  to study charging rate and distribution in a thin walled dielectric wakefield accelerator from a passing charge bunch, and

  the physics of conductivity and discharge phenomena leading to damage in dielectric materials useful for accelerator applications.

• The issue is the role played by the beam halo and intense wakefields in charging of the dielectric,

    Not thoroughly studied yet;

    Can lead to undesired deflection of charge bunches and degradation of the dielectric material.

• Plans are to make measurements on a DWA (dielectric wakefield accelerator) system
Approach and Method:

1) The detector will measure the change in complex electrical conductivity inside the dielectric tubing that is caused by the passage of a charged relativistic electron bunch.

Detector is based on measurement of the change of complex admittance of a resonant microwave cavity.

Cavity is fitted around the dielectric tubing (that has the complex electrical conductivity).

2) The detector can detect permanent damage to the material, and transient phenomenon accompanying the passage of one or more charged bunches.
3) Microwave apparatus was built, and

Signal processing was developed for observing time-dependent electronic charging of dielectric surfaces and/or plasmas.

4) The test and performance results for a plasma test case will be presented;

in particular, capability to detect small changes $\sim 0.1\%$ of a dielectric constant,

which corresponds to the scraping-off of only $0.3\text{nC}$ to the walls of the dielectric liner.
Generic schematic of the measurement system. Only principal elements are shown.

Equivalent circuit for a resonant cavity

$\Delta g_d$ and $\Delta b_d$ are the changes in dielectric conductance and susceptance (normalized to the PP'-plane);
$g_c$ and $b_c$ are the cavity conductance and susceptance when the dielectric is not affected by wakefields or halo electrons;
$g_l$ is the conductance of the RF-feeding line and the input coupling;
$g_t$ is the output coupling (assumed to be small);
$P_i$ stands for the incident power; $P_t$ - for the transmitted power; and $P_r$ - for the reflected one.
Using the cavity resonant treatment

\[
\frac{P_i}{P_t} \frac{4q_t}{[1+(1/q_t+1)q]^2} = 1 + \frac{(1/q_t+1)^2}{[1+(1/q_t+1)q]^2} \Delta b_d^2 \frac{(f-F_0')^2}{(F_0'-F_0')^2}
\]

\[
q_d + jb_d = \frac{\beta \int \Delta \sigma E^2 dv}{\omega_0 \varepsilon_0 \int E^2 dv}
\]

where either \( g = g_c + g_t + \Delta g_d \) or \( g = g_c + g_t \) depending if the dielectric is affected by the halo electrons and wakefields or not, \( F_0' \) and \( F_0 \) are the cavity resonance frequencies for each respective case, and \( f \) is the scanning frequency (frequency of incident RF). \( \beta \) is the cavity coupling. The integrals are taken over the cavity volume, \( \omega_0 = 2\pi F_0 \), \( E \) is the vector electric field, and \( \Delta \sigma \) is the change in the complex conductivity.

To go further, use

\[
Q^2 = \frac{\beta^2 (1/q_t+1)^2}{[1+(1/q_t+1)q]^2}
\]

where \( Q \) is the cavity Q-factor.
the ratio, \( T_m \equiv (P_t/P_i)_m \), for each observer (generator) frequency, \( f_m \)

\[
T_m = \xi \frac{(Q/Q_\xi)^2}{1 + Q^2 \left( \frac{2 f_m - F}{F} \right)^2} \approx \xi \frac{(Q/Q_\xi)^2}{1 + Q^2 \left( \frac{2 f_m - F}{F_\xi} \right)^2}
\]

where \( \xi = (P_t/P_i)_\xi \) is the transmission (power ratio) when there is no charge present, and similarly, \( F_\xi \) and \( Q_\xi \) are the resonant frequency and the q-factor respectively. \( F \) and \( Q \) are the resonant frequency and q-factor when there is a discharge, etc.

\[
F = \frac{f_m + f_k}{2} + \frac{F_\xi^2}{f_m - f_k} \frac{T_m - T_k}{\xi} \frac{\xi^2}{T_m T_k} \frac{1}{8Q_\xi^2}
\]

\[
\frac{1}{Q^2} = \frac{\xi}{T_k} \frac{1}{Q_\xi^2} - \left( \frac{f_m - f_k}{F_\xi} + \frac{F_\xi}{f_m - f_k} \frac{T_m - T_k}{\xi} \frac{\xi^2}{T_m T_k} \frac{1}{4Q_\xi^2} \right)^2
\]
Diagram of the experimental setup: to record three different traces, the probing frequency (of the CW RF generator) was adjusted, and the discharge event was repeated.

**Choice 1:** \( f_1 \approx F_\xi; f_2 \approx F_\xi + (BW_\xi/2) \) and \( f_3 \approx F_\xi + BW_\xi \)

**Choice 2:** \( f_1 \approx F_\xi - (BW_\xi/2); f_2 \approx F_\xi \) and \( f_3 \approx F_\xi + BW_\xi/2 \)

\[ F_\xi = 2479.157 \text{ MHz}, \quad Q_\xi = 1175, \quad \text{and} \quad BW_\xi = F_\xi / Q_\xi = 2.11 \text{ MHz} \]
Microwave signals transmitted through the resonator which is loaded with plasma, using three different frequencies.

Current behavior during the time when microwave signals are observed.

Traces were recorded at three observer frequencies:

- $f_1 = 2479.1936\, \text{MHz} \approx \text{resonant frequency}$ (RED)
- $f_2 = 2480.276\, \text{MHz}$ (BLUE)
- $f_3 = 2481.141\, \text{MHz}$ (BROWN)

*Input power stays the same*
Changes in the resonant Frequency (MHz) vs. Time (ms)

Changes in the Q-factor vs. Time (ms).

This is plotted as \((1/Q - 1/Q_{\xi})\), where the latest in the Q-factor when there is no plasma.
\[
\frac{\Delta \varepsilon}{\varepsilon} = 1 + A \frac{F - F_\xi}{F_\xi} + B \left( \frac{F - F_\xi}{F_\xi} \right)^2 + \ldots
\]

\[
\Delta (\text{loss tan}) = C \left( \frac{1}{Q} - \frac{1}{Q_\xi} \right) \left( 1 + D \frac{F - F_\xi}{F_\xi} + E \left( \frac{F - F_\xi}{F_\xi} \right)^2 + \ldots \right)
\]

\[
\varepsilon_{\text{Im}} = \varepsilon_{\text{Re}} \cdot \text{loss tan}
\]

To find the coefficients A, B, ... and E we will

* use e.g. HFSS,

* do simulations having changes in the medium $\varepsilon$, and loss-tan, and find the corresponding changes in the cavity’s frequency and Q-factor.

* once the dependences are found, we reverse them
Example:

\[
\frac{\Delta \varepsilon}{\varepsilon_{ini}} = 1 + (-22.5579) \frac{F - F_\xi}{F_\xi} + (-5.4125 \cdot 10^{-4}) \left( \frac{F - F_\xi}{F_\xi} \right)^2
\]

\[
\Delta (\text{loss tan}) = (11.3047) \left( \frac{1}{Q} - \frac{1}{Q_\xi} \right) \left( 1 + (22.5814) \frac{F - F_\xi}{F_\xi} + (648.7763) \left( \frac{F - F_\xi}{F_\xi} \right)^2 \right)
\]

\[
\varepsilon_{im} = (11.3047) \left( \frac{1}{Q} - \frac{1}{Q_\xi} \right)
\]
Changes in the loss-tan and the Imaginary part of dielectric constant vs. Time (ms)

Changes in Real part of dielectric constant vs. Time (ms)

0.2% - 0.1% of the initial dielectric constant
To find corresponding changes in the density of free electrons, we will use reasonable assumption about our medium under test

For instance for the case described here, we also can use well known relationships between the density of free electrons, \( n_e \), and their collision frequency, \( F_{\text{coll}} \) and the plasma dielectric constant \( \varepsilon_0 (\varepsilon_{\text{Re}} + j \varepsilon_{\text{Im}}) \)

\[
\varepsilon_{\text{Re}} = 1 - \frac{n_e \cdot e^2}{m_e \varepsilon_0 (2\pi F_\xi)^2} \frac{1}{1 + \left(\frac{F_{\text{coll}}}{F_\xi}\right)^2}
\]

\[
\varepsilon_{\text{Im}} = \frac{n_e \cdot e^2}{m_e \varepsilon_0 (2\pi F_\xi)^2} \frac{F_{\text{coll}}}{F_\xi} \frac{1}{1 + \left(\frac{F_{\text{coll}}}{F_\xi}\right)^2}
\]
Electron density ($\times 10^9$ cm$^{-3}$) vs Time
Charge (nC) vs. Time (ms)
**few Conclusions**

- can detect the densities at or even above $10^{10}$ cm$^{-3}$ [50- 60 nC]
- can detect electron density at or even below $~10^8$ cm$^{-3}$ [ 0.5 nC]
- dynamic range $\sim$20 dB [ for our simple, not sophisticated, setup ]

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**few Considerations**

- The upper limit will be greater when a more powerful RF generator and more sensitive detectors (and output amplifiers) are employed.
- The lower limit can be improved by increasing the cavity Q-factor. This follows from $N_e \sim BW_\xi$ at low densities of free electrons. E.g.:

  In our present setup has $Q \sim 1000$, and the minimum charge $N_{e, \text{min}} \sim 0.5 \text{ nC} [10^8 \text{ cm}^{-3}]$

  $Q \sim 3000$ will still allow us to capture the processes on the micro-sec time-scale, yet the min. change $\sim 0.15 \text{ nC} [3\div4 \times 10^7 \text{ cm}^{-3}]$
Diagram of a detector to install at an accelerator: 1 – tunable frequency generators (3x); 2 - circulators (3x); 3 – variable amplifier (3x); 4 – power combiners (2x); 5 – fast RF switches (2x); 6 – cavity with samples under test; 7 – high frequency output amplifier; 8 – local oscillator; 9 – mixer; 10 – band-pass frequency filters (3x); 11 – crystal detectors (3x); 12 – low frequency amplifiers (3x); 13 – oscilloscope; 14 – GPIB/USB-Ethernet/USB adapter; 15 – computer.
Dielectric constant and loss-tan of Quartz (pure) and Alumina (99.6% pure) near 2.5 GHz

Samples were ordered from two manufacturers: [http://technicalglass.com](http://technicalglass.com) and [http://advaluetech.com](http://advaluetech.com).

The quartz samples were either 13×15 mm or 12×16mm (ID×OD); the alumina samples were either 9.51 × 13.02 mm or 9.585 × 12.91 mm. We denote these samples by following code–names: Q13:15, Q12:16, A9.51:13.02, and A9.59:12.91.

<table>
<thead>
<tr>
<th>Sample</th>
<th>Material</th>
<th>Changes in Frequency (MHz)</th>
<th>Changes in 1/Q</th>
<th>Dielectric constant**</th>
<th>Loss-tan***</th>
</tr>
</thead>
<tbody>
<tr>
<td>Q13:15</td>
<td>Quartz</td>
<td>-83.57</td>
<td>*</td>
<td>3.408</td>
<td>&lt; 1 × 10⁻⁵</td>
</tr>
<tr>
<td>Q12:16</td>
<td>Quartz</td>
<td>-162.67</td>
<td>*</td>
<td>3.391</td>
<td>&lt; 1 × 10⁻⁵</td>
</tr>
<tr>
<td>A9.51:13.02</td>
<td>Alumina</td>
<td>-313.06</td>
<td>3.86 × 10⁻⁴</td>
<td>8.731</td>
<td>1.38 × 10⁻³</td>
</tr>
<tr>
<td>A9.59:12.91</td>
<td>Alumina</td>
<td>-289.28</td>
<td>2.85 × 10⁻⁴</td>
<td>8.023</td>
<td>1.09 × 10⁻³</td>
</tr>
</tbody>
</table>

* cannot be measured within the measurement accuracy;

** \( \Delta \varepsilon = 6 \times 10^{-3} \);

***\( \Delta(\text{losstan}) \leq 1 \cdot 10^{-5} \) (for Quartz); and \( \Delta(\text{losstan}) \leq 5 \cdot 10^{-5} \) (for Alumina)
Bibliography:


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